

Search Notes



Application/Control No.

10/717,284

Examiner

Hiep Nguyen

Applicant(s)/Patent under Reexamination

TAFT ET AL.

Art Unit

2816

SEARCHED

Class	Subclass	Date	Examiner
327	403	05.04.05	Na
	404	I	I
326	113	I	I

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EAST		
See attachment	05.04.05	Na